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Applicant(s)/Patent under Reexamination

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PATFIELD, KEVIN M.
Art Unit

Syed Zaidi

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SEARCHED			
Class	Subclass	Date	Examiner
370	352	8/8/2007	SZ
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EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	8/8/2007 ·	SZ
Inventor: Patfield Kevin et al	8/8/2007	SZ
(IEEE Xplore Database(http://ieeexplore.ieee.org/Xp lore/DynWel.jsp)	8/8/2007	SZ
(370/352 370/351 370/359 370/379 370/353 370/354 370/355 370/357).CCLS.	8/8/2007	SZ
Consulted with SPE Seema S.Rao	8/8/2007	SZ
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